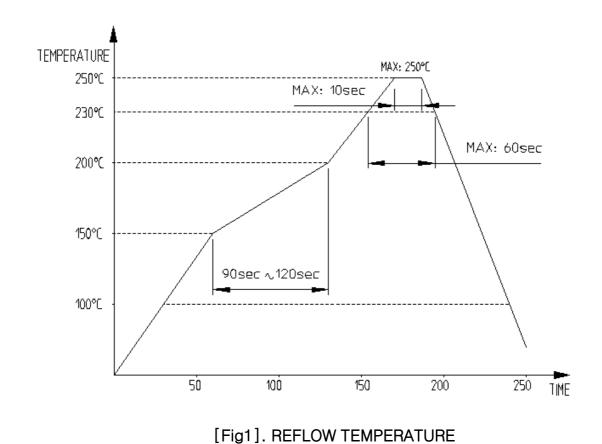
REV	COUNT DESCRIPTION OF REVISIO			BY	CHKD	DATE	REV	COUNT	DES	CRIPTION OF REVISI	CHKD	DA	\TE	
/î\	- Revised			JH.B00	HJ.KIM	17.02.14	3	-	Revise	d	HJ.LEE	17.1	0.13	
<u>^</u> 2\	- Revised			JH.B00	HJ.LEE	17.05.11	4	1	Revise	d	HJ.LEE	18.0	3.06	
APPLICABLE STANDARD														
RATING				DC 1.25A max. for each power pin (i.e. A1, A4, A9, A12, B1, B4, B5, B9, B12) DC 0.25A for the other pins										
VOLTAGE				20VAC										
4 OPERATING CONDITION				-40° ~ +85° (INCLUDING TEMP. RISE), 95% RH MAX.(NON-CONDENSING)										
	STORAGE CONDITION −10° ~ +60° (WITH PACKING), 15% ~ 70% RH							1						
Para.	a. Test Description			Test Procedure						Test Requirement				ΑТ
1	I Examination of product I			A 364-18 sual inspection						No physical damage				0
Electi	rical Require	ments	•											
2	2 Low Level Contact Resistance			EIA 364-23 Measure at 20mV max open circuit at I00mA(DC OR 1000Hz). Mewire measurement is required and the resistance of PCB termination shall be deducted from the reading.						40m Ω max initial for each contact. 50m Ω max after initial measurement.				-
3	Dielectric Withstanding Voltage			EIA 364-20 Measure per Method B with unmated condition. 100VAC RMS for 1 minute at sea level.					١	No disruptive discharge.				_
I 4 I Inquilation Registance I			EIA 364-21 500VDC with unmated and mated condition.					on.	100MΩ Min.				1	
Mech	anical Requi	rements												
5	Insertio	on force	EIA 36 Measu		2.5mm,	/minute	min.		5	5N to 20N			0	1
6	S I Extraction torce I			EIA 364-13 Measure at 12.5mm/minute min.						Initial: 8N to 20N After test: 6N to 20N				1
7	EIA 364-09 Durability 10,000 insertion/ext Cycle rate: 500±50				-			ď	Low level contact resistance and dielectric withstanding voltage shall meet the spec after test.			0	-	
8	Vibi	ration	Test C 20-50	est Condition VII, Test Letter D 0-500 Hz random levels, 15minutes in				No physical damage and no discontinuity longer than 1us. Low level contact resistance shall meet spec before and after the test.			0	_		
REMARKS			I			DRA	AFT	DE	SIGN	CHECK	APPROVAL	REL	EAS	E
Unless otherwise specified, refer to the specifications for USB Type-c, EIA 364					H.J. 16.0	KIM	KN.ICI		WA H.J.LEE	T.S.KANG 16.08.03	18.03.08			
NOTE) QT : QUALIFICATION TEST, AT : ASSURANCE TEST, O: Applicable Test														
DWG NO CL NO CL NO CL (6240	6240-0004-7 CX90			90B1-2	B1-24P					
10	THE HIDORE KODEA CO. LTD.											1	/	

Para.	Test Description	Test Procedure	Test Requirement	QT	ΑТ			
Enviro	Environmental Requirements							
u i iamnaratiira iita i		EIA 364-17, Method A 105℃ without applied voltage for 120hours.	Low level contact resistance shall meet spec before and after the test.	0	-			
10	Cyclic Temperature and Humidity	EIA 364-31 25±3°C at 80±3% RH for 1 hour. 65±3°C at 50±3% RH for 1 hour. Thermal ramp: 0.5 hour Number of cycles: 24 cycles	Low level contact resistance shall meet spec before and after the test.	0	1			
11	Thermal Shock	EIA 364-32, Test Condition I 10cycles -55°C and +85°C	No physical damage. Low level contact resistance shall meet spec before and after the test.	0	_			
12	Solderability	EIA 364-52 Dwell in 245℃±5℃ of the solder bath for 5sec.	Solder coverage shall be 95% min.of the immersed surfaces.	0	_			
13	Salt Spray	EIA 364-26 5% of NaCl in 35℃ for 48hours	No corrosions that affect to connector operation. Low level contact resistance shall meet spec before and after the test.	0	_			
14	Reflow test (Co-planarity)	Reflow profile[Fig1] Peak 250°C max. For 10 sec 2 times.	 ① 0.1max before reflow ② 0.1max after reflow ③ No deformation of mold ④ No shape of blister and popcorn 	0	_			

REMARKS



NOTE) QT : QUALIFICATION TEST, AT : ASSURANCE TEST, O: Applicable Test

DWG NO CL NO PART NO CX90B1-24P

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PRODUCT SPECIFICATION

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Qualification Test Sequence Table											
		Test Group									
Para.	Test Description	Α	В	С	D	E	F	G	Н		
1	Examination of product	0	0	0	0	0	0	0	0		
2	Low Level Contact Resistance	0	0	0	0	0		0			
3	Dielectric Withstanding Voltage		0								
4	Insulation Resistance		0								
5	Insertion force		0								
6	Extraction force		0								
7	Durability		0								
8	Vibration	0									
9	Temperature Life			0							
10	Cyclic Temperature and Humidity				0						
11	Thermal Shock					0					
12	Solderability						0				
13	Salt Spray							0			
14	Reflow test (Co-planarity)								0		

REMARKS

NOTE) QT : QUALIFICATION TEST, AT : ASSURANCE TEST, O: Applicable Test

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ELC4-632149 CL 6240-0004-7 CX90B1-24P



¹⁾ Numbers in the table above indicate the sequence corresponding to each test group.